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YB

**INDUSTRY STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

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**Preparation of Sectional Specimens of Metallic Materials -
Focused Ion Beam Method
(English Translation)**

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What this standard covers

This standard specifies the instruments and equipment, sample pretreatment, preparation conditions, and steps for preparing cross-sectional samples of metallic materials using focused ion beams. This standard applies to the preparation of cross-sectional samples of metallic materials, including substrates, surface coatings, and corrosion layers. Other materials may refer to this standard.

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